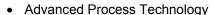


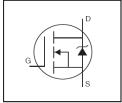
AUTOMOTIVE GRADE

AUIRFS6535 AUIRFSL6535

HEXFET® Power MOSFET



- Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- · Lead-Free, RoHS Compliant
- Automotive Qualified *

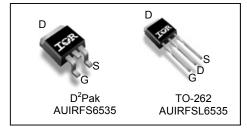


$\begin{array}{c|c} V_{DSS} & 300V \\ \hline R_{DS(on)} \ typ. & 148 m \Omega \\ \hline max. & 185 m \Omega \\ \hline I_D & 19A \\ \hline \end{array}$

Description

Features

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



G	D	S
Gate	Drain	Source

Base next number	Dookogo Typo	Standard Pack		Orderable Part Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRFSL6535	TO-262	Tube	50	AUIRFSL6535
ALUDECESE	D²-Pak	Tube	50	AUIRFS6535
AUIRFS6535 D ² -Pak		Tape and Reel Left	800	AUIRFS6535TRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	19	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	13	Α
I _{DM}	Pulsed Drain Current ①	100	
P _D @T _C = 25°C	Maximum Power Dissipation	210	W
	Linear Derating Factor	1.4	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS} Single Pulse Avalanche Energy (Thermally Limited) ②		216	
E _{AS} (tested)	AS (tested) Single Pulse Avalanche Energy Tested Value ®		- mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E _{AR}	Repetitive Avalanche Energy S		mJ
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.71	°C/W
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount, steady state) ூ		40	C/VV

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	300			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.39		V/°C	Reference to 25°C, I _D = 5.0mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		148	185	mΩ	V _{GS} = 10V, I _D = 11A ③
$V_{GS(th)}$	Gate Threshold Voltage	3.0		5.0	٧	$V_{DS} = V_{GS}$, $I_D = 150\mu A$
gfs	Forward Trans conductance	15			S	$V_{DS} = 50V, I_{D} = 11A$
	Drain to Course Leakage Current			20		$V_{DS} = 300V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 300V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	n ^	V _{GS} = 20V
IGSS	Gate-to-Source Reverse Leakage			-100	nA	V _{GS} = -20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Q_g	Total Gate Charge	 38	57		I _D = 11A
Q_{gs}	Gate-to-Source Charge	 12		nC	V _{DS} = 150V
Q_{gd}	Gate-to-Drain Charge	 13			V _{GS} = 10V3
$t_{d(on)}$	Turn-On Delay Time	 15			V _{DD} = 300V
t _r	Rise Time	 16		ns	I _D = 11A
$t_{d(off)}$	Turn-Off Delay Time	 22		115	$R_G = 5.0\Omega$
t _f	Fall Time	 10			V _{GS} = 10V ③
L _D	Internal Drain Inductance	 4.5			Between lead, 6mm (0.25in.)
Ls	Internal Source Inductance	 7.5			from package and center of die contact
C _{iss}	Input Capacitance	 2340			$V_{GS} = 0V$
C _{oss}	Output Capacitance	 195			V _{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	 40		"F	f = 1.0MHz
C_{oss}	Output Capacitance	 1750		pF	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
Coss	Output Capacitance	 66			$V_{GS} = 0V$, $V_{DS} = 240V$ $f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 130			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 240V $

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current (Body Diode)			19		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			100		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 11A, V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		190	285	ns	$T_J = 25^{\circ}C$, $I_F = 11A$, $V_{DD} = 150V$
Q_{rr}	Reverse Recovery Charge		990	1485	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Limited by T_{Jmax} , starting $T_J = 25$ °C, L = 3.6mH, $R_G = 50\Omega$, $I_{AS} = 11$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.
- ③ Pulse width \leq 1.0ms; duty cycle \leq 2%.
- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- ® This value determined from sample failure population, starting $T_J = 25$ °C, L = 3.6mH, $R_G = 50\Omega$, $I_{AS} = 11A$, $V_{GS} = 10V$.
- This is applied to D²Pak When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ® R_θ is measured at T_J approximately 90°C.



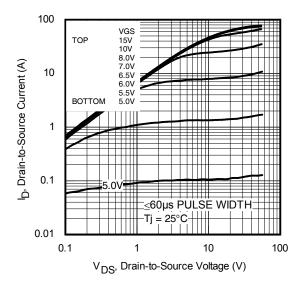


Fig. 1 Typical Output Characteristics

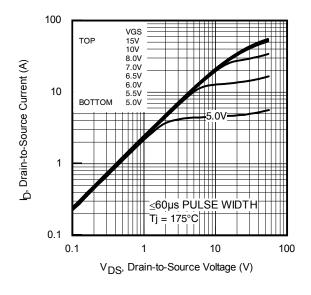


Fig. 2 Typical Output Characteristics

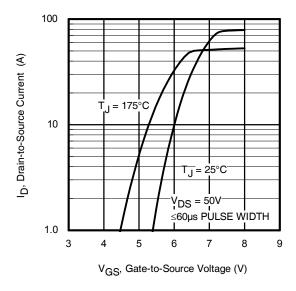


Fig. 3 Typical Transfer Characteristics

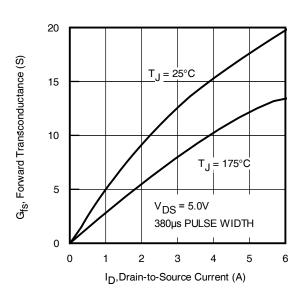


Fig. 4 Typical Forward Trans conductance vs. Drain Current



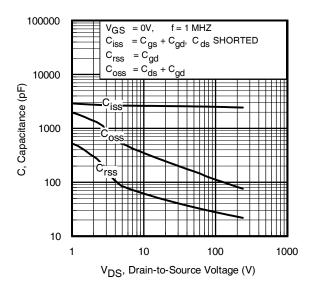


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

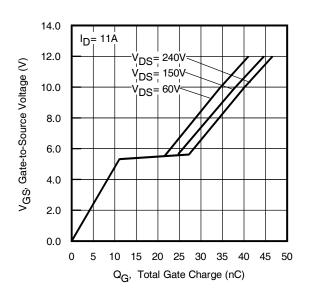


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

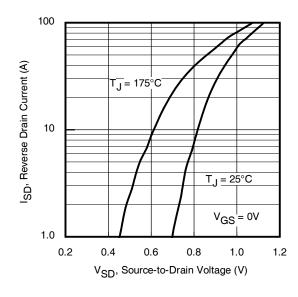


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

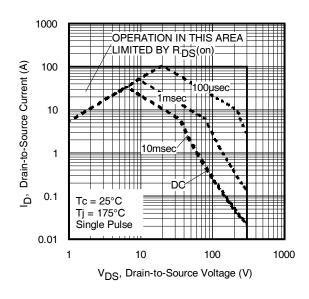
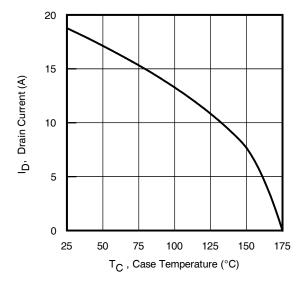


Fig 8. Maximum Safe Operating Area

4





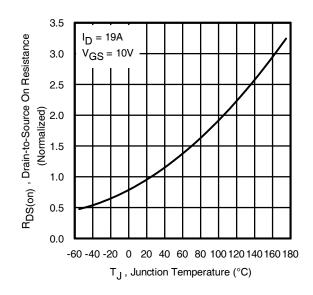


Fig 9. Maximum Drain Current vs. Case Temperature

Fig 10. Normalized On-Resistance vs. Temperature

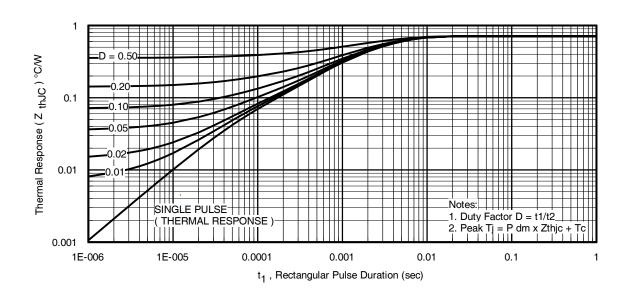


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



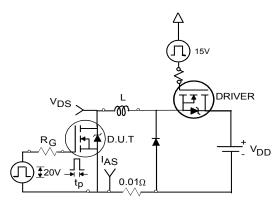


Fig 12a. Unclamped Inductive Test Circuit

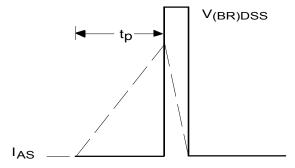


Fig 12b. Unclamped Inductive Waveforms

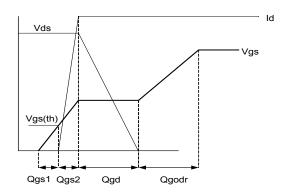


Fig 13a. Gate Charge Waveform

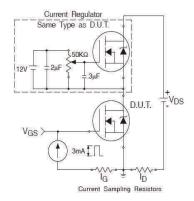


Fig 13b. Gate Charge Test Circuit

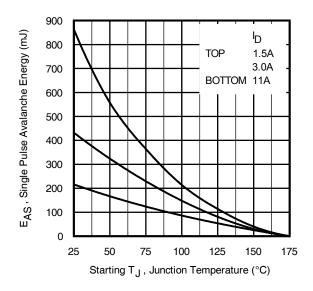


Fig 12c. Maximum Avalanche Energy vs. Drain Current

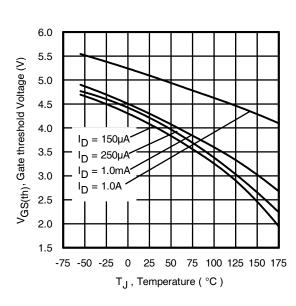


Fig 14. Threshold Voltage vs. Temperature



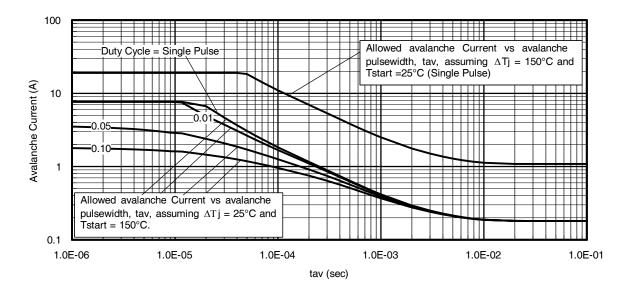


Fig 15. Typical Avalanche Current vs. Pulse width

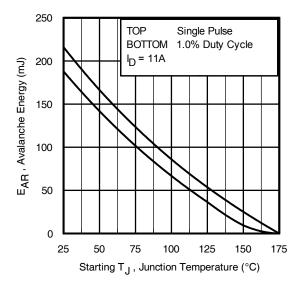


Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- 1. Avalanche failures assumption:
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



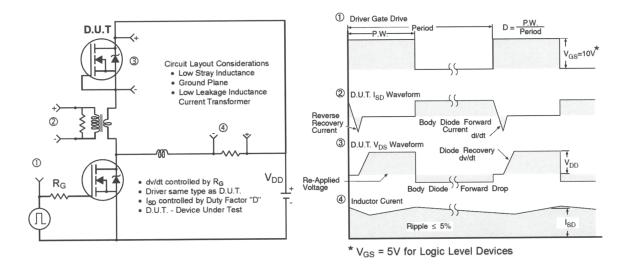


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

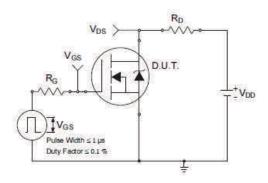


Fig 18a. Switching Time Test Circuit

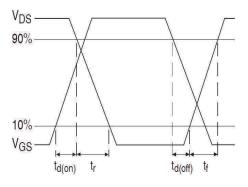
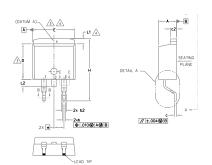
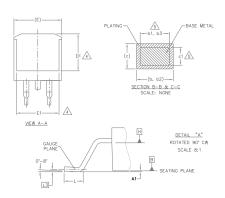


Fig 18b. Switching Time Waveforms



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S		N			
M B	MILLIMETERS INCHES			O T E S	
0 L	MIN.	MAX.	MIN.	MAX.	S
А	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270	_	4
Е	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245	_	4
е	2.54	BSC	.100	BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

LEAD ASSIGNMENTS

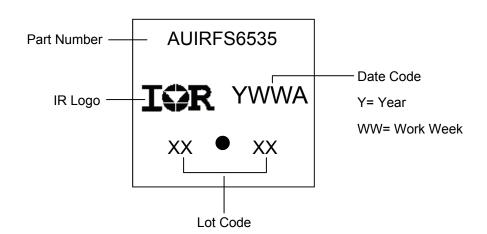
DIODES

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

HEXFET

IGBTs, CoPACK 1.- GATE 2, 4.- DRAIN 3.- SOURCE 2, 4.- COLLECTOR 3.- EMITTER

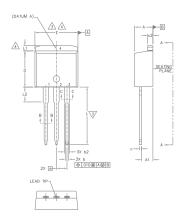
D²Pak (TO-263AB) Part Marking Information

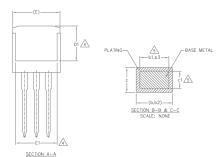


2015-12-4



TO-262 Package Outline (Dimensions are shown in millimeters (inches)





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3\DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

HEXFET DIODES

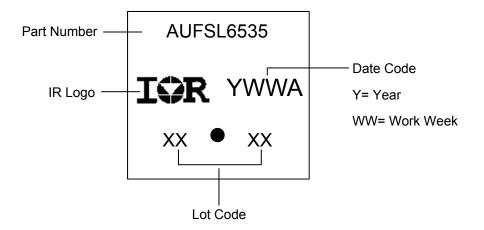
1.- GATE

2.- DRAIN 3.- SOURCE 4.- DRAIN

1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

S Y M		N			
В	MILLIMETERS		METERS INCHES		
0 L	MIN.	MAX.	MIN.	MAX.	O T E S
Α	4.06	4.83	.160	.190	
A1	2.03	3.02	.080	.119	
b	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
b3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	-	.270	_	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245		4
е	2.54	BSC	.100	BSC	
L	13.46	14.10	.530	.555	
L1	_	1.65	_	.065	4
L2	3.56	3.71	.140	.146	

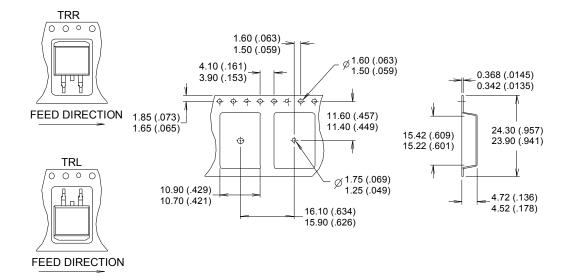
TO-262 Part Marking Information

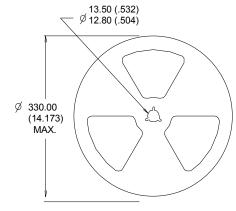


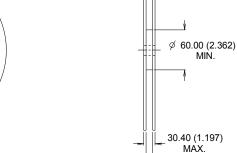
10 2015-12-4



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







26.40 (1.039)

24.40 (.961)

3

MIŇ.

4

27.40 (1.079) 23.90 (.941) 4

NOTES:

- COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 3
- DIMENSION MEASURED @ HUB.
 INCLUDES FLANGE DISTORTION @ OUTER EDGE.

11 2015-12-4



Qualification Information

		A				
		Automotive (per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture Sensitivity Level		MSL1				
		11021				
Manalaina Manalai		Class M2 (+/-200) [†]				
Macrime Moder	AEC-Q101-002					
House and Deadle Medical	Class H1B (+/-1000V) [†]					
Human Body Model	AEC-Q101-001					
Observed Davids a Madal	Class C5 (+/-2000V) [†]					
Charged Device Model		AEC-Q101-005				
RoHS Compliant		Yes				
	Machine Model Human Body Model Charged Device Model	Industrial and C Automotive leve TO-262 D²-Pak Machine Model Human Body Model Charged Device Model				

† Highest passing voltage.

Revision History

Date	Comments		
12/4/2015	Updated datasheet with corporate template		
12/4/2013	Corrected ordering table on page 1.		

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